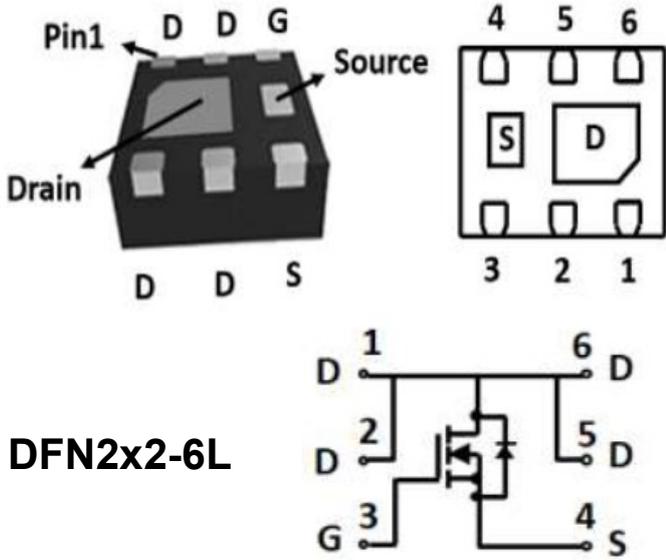


## N-Channel Enhancement Mode Field Effect Transistor



DFN2x2-6L

### Product Summary

- $V_{DS}$  20V
- $I_D$  13A
- $R_{DS(ON)}$ ( at  $V_{GS}=4.5V$ ) <9mohm
- $R_{DS(ON)}$ ( at  $V_{GS}=2.5V$ ) <12mohm
- $R_{DS(ON)}$ ( at  $V_{GS}=1.8V$ ) <18.5mohm
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Trench Power LV MOSFET technology
- High density cell design for Low  $R_{DS(ON)}$
- High Speed switching

### Applications

- Battery protection
- Load switch
- Power management

### ■ Absolute Maximum Ratings ( $T_A=25^\circ C$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		$V_{DS}$	20	V
Gate-source Voltage		$V_{GS}$	$\pm 10$	V
Drain Current	$T_A=25^\circ C$	$I_D$	13	A
	$T_A=70^\circ C$		8	
Pulsed Drain Current <sup>A</sup>		$I_{DM}$	32	A
Total Power Dissipation	$T_A=25^\circ C$	$P_D$	2.2	W
	$T_A=70^\circ C$		1.4	
Thermal Resistance Junction-to-Ambient <sup>B</sup>		$R_{\theta JA}$	57	$^\circ C/W$
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55~+150	$^\circ C$

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCQ10N02A	F1	Q10N02	3000	30000	120000	7" reel

## ■ Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V			1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±10V, V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.45	0.62	1.0	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =13A		7.8	9	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =6.5A		9.5	12	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =4A		12	18.5	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =13A, V <sub>GS</sub> =0V			1.2	V
<b>Dynamic Parameters</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1MHZ		888		pF
Output Capacitance	C <sub>oss</sub>			133		
Reverse Transfer Capacitance	C <sub>rss</sub>			117		
<b>Switching Parameters</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =6.8A		11.05		nC
Gate-Source Charge	Q <sub>gs</sub>			1.73		
Gate-Drain Charge	Q <sub>gd</sub>			3.1		
Turn-on Delay Time	t <sub>D(on)</sub>	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =6.8A R <sub>GEN</sub> =3Ω		7		ns
Turn-on Rise Time	t <sub>r</sub>			46		
Turn-off Delay Time	t <sub>D(off)</sub>			30		
Turn-off fall Time	t <sub>f</sub>			52		

A. Pulse Test: Pulse Width ≤ 300us, Duty cycle ≤ 2%.

B. R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design, while R<sub>θJA</sub> is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

■ Typical Performance Characteristics

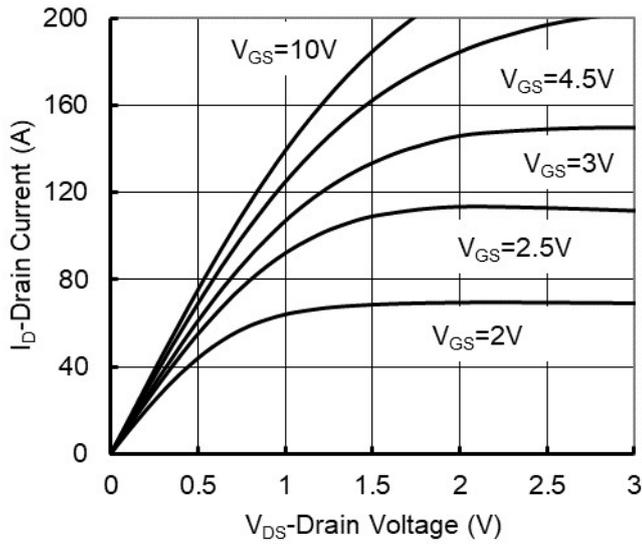


Figure1. Output Characteristics

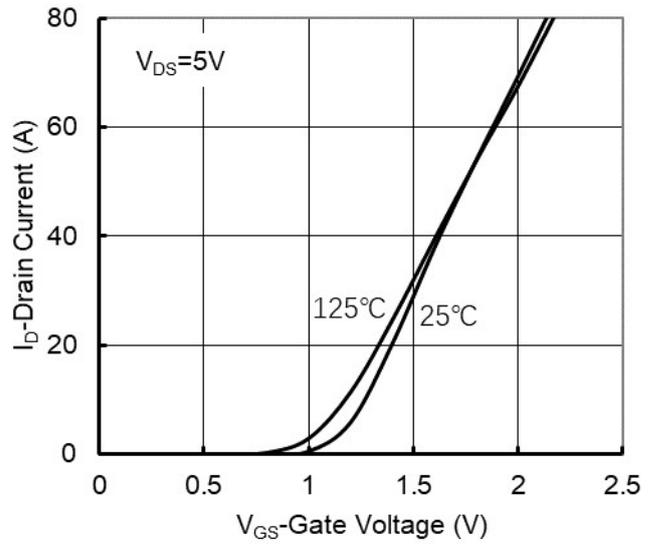


Figure2. Transfer Characteristics

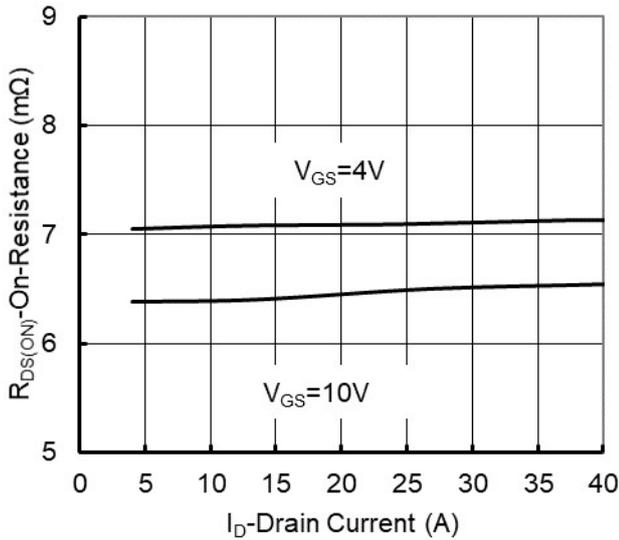


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

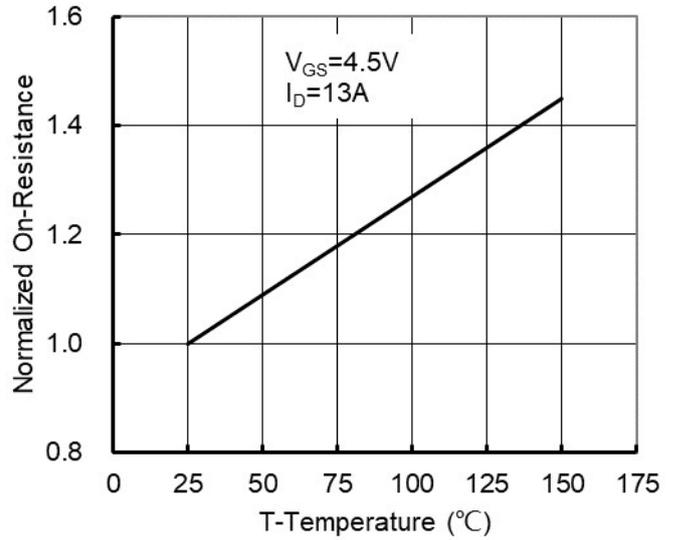


Figure 4: On-Resistance vs. Junction Temperature

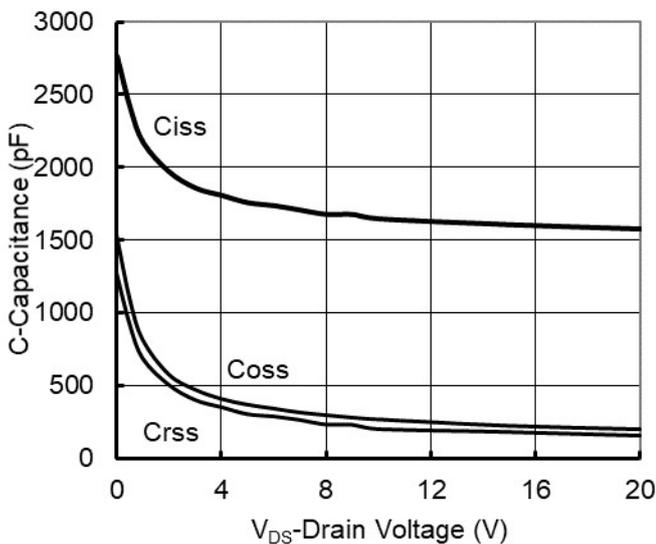


Figure5. Capacitance Characteristics

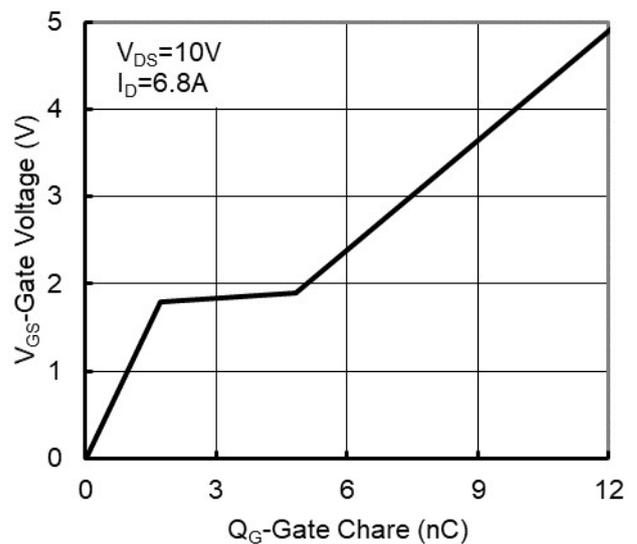


Figure6. Gate Charge

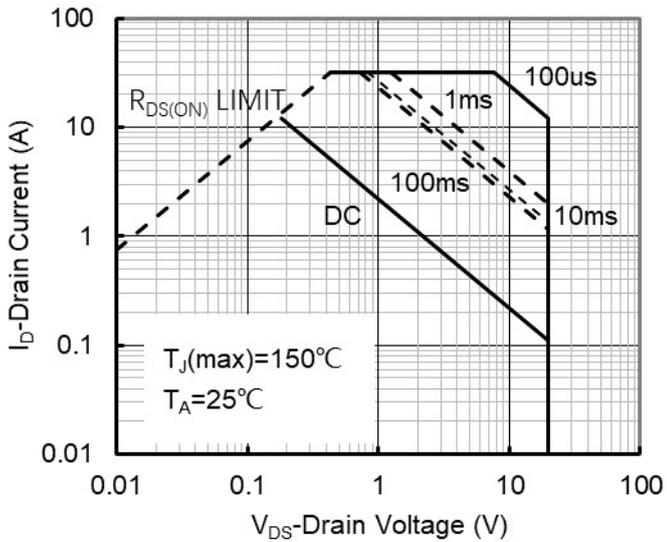


Figure7. Safe Operation Area

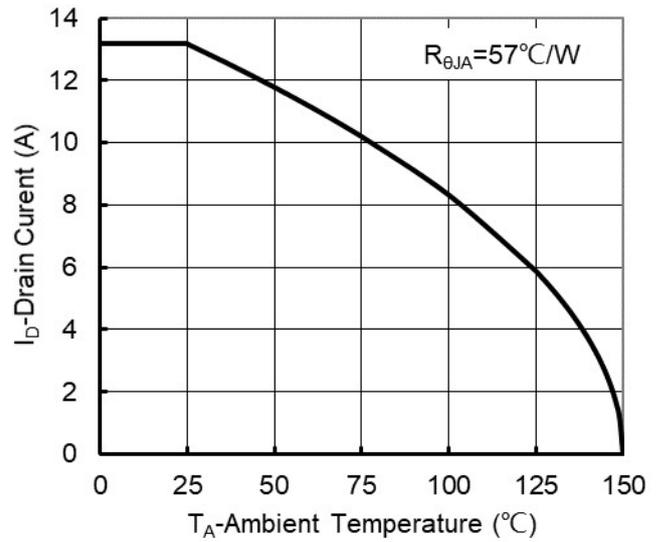


Figure8. Maximum Continuous Drain Current vs Ambient Temperature

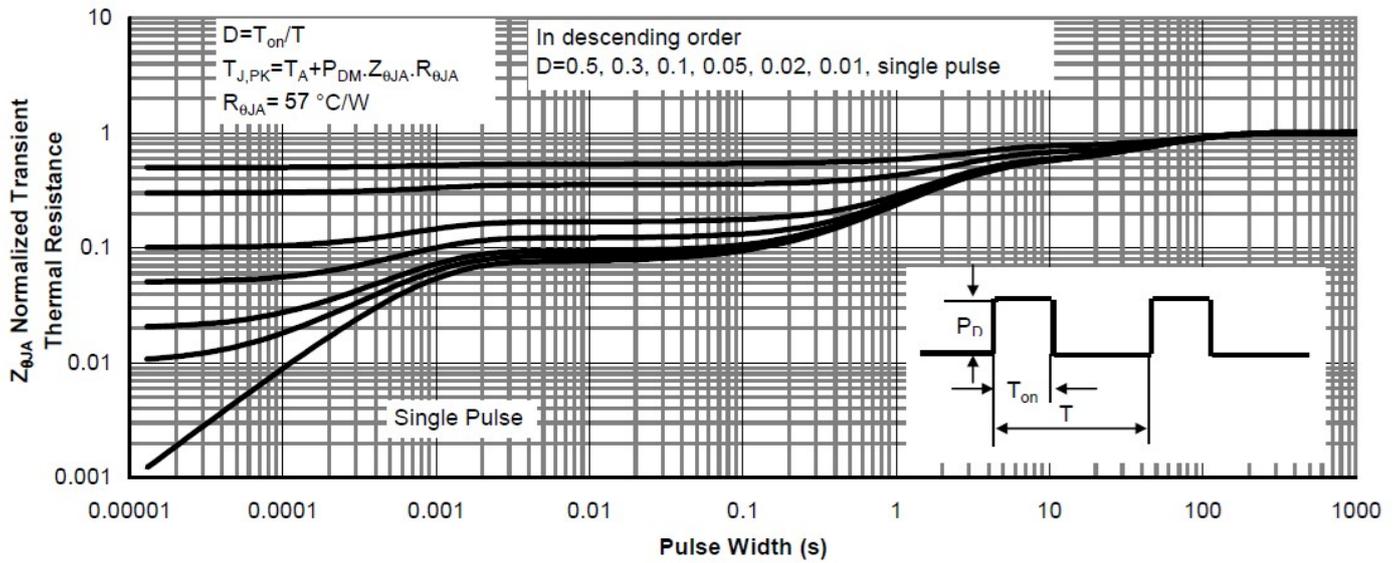
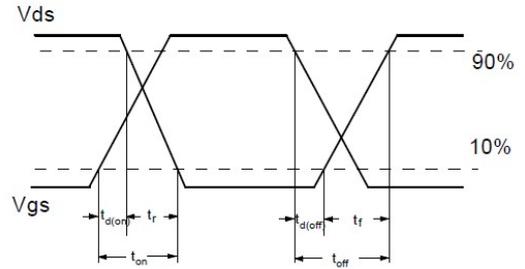
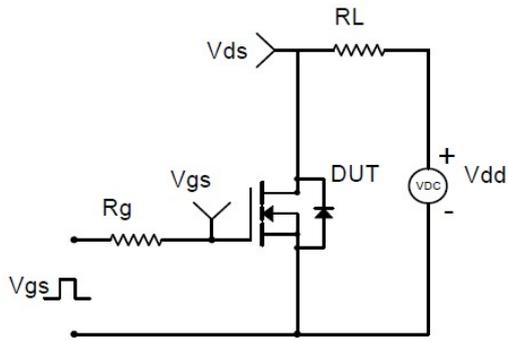
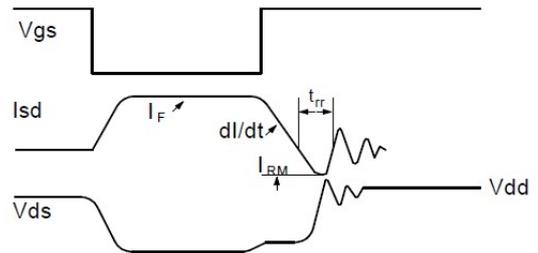
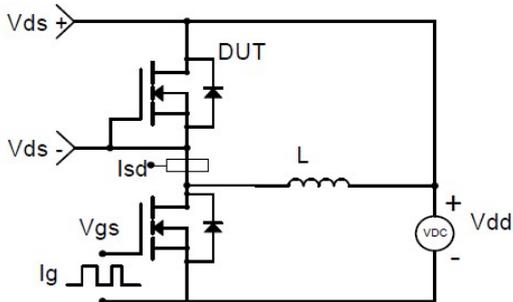


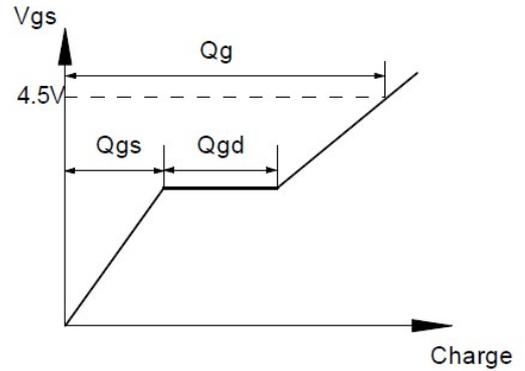
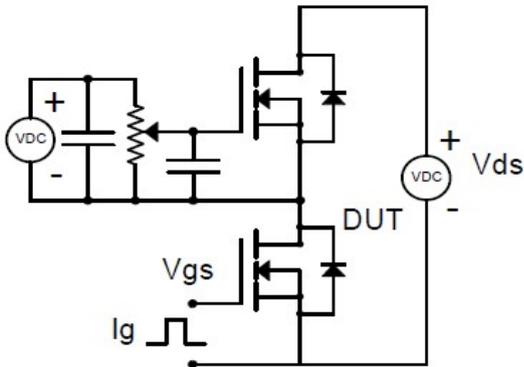
Figure9. Normalized Maximum Transient Thermal Impedance



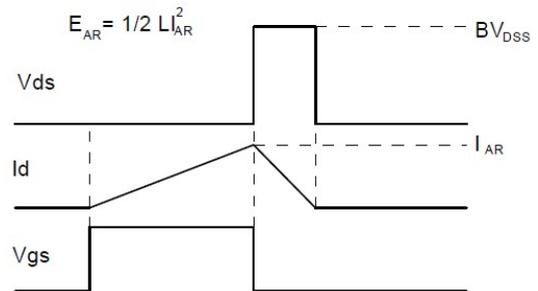
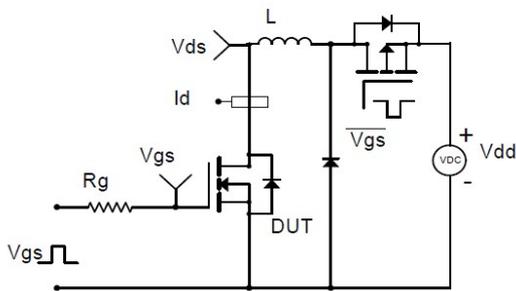
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

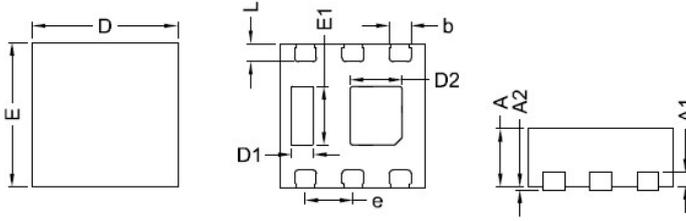


Gate Charge Test Circuit & Waveform



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

■ DFN2x2-6L Package information

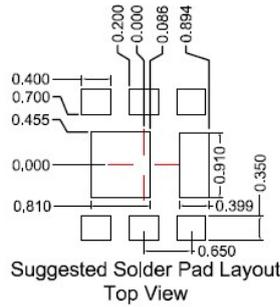


Top View  
正面视图

Bottom View  
背面视图

Side View  
侧面视图

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	1.90	2.00	2.10
E	1.90	2.00	2.10
A	0.70	0.80	0.90
A1	0.20 BSC		
A2			0.10
D1	0.20	0.30	0.40
D2	0.61	0.71	0.81
E1	0.71	0.81	0.91
L	0.15	0.25	0.35
b	0.20	0.30	0.40
e	0.65 BSC		



- Note:
1. Controlling dimension: in millimeters.
  2. General tolerance:  $\pm 0.10\text{mm}$ .
  3. The pad layout is for reference purposes only.

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